

## 650V Cascode GaN FET in TO-247 (source tab)

#### Description

The TP65H035WS 650V,  $35m\Omega$  Gallium Nitride (GaN) FET is a normally-off device. It combines state-of-the-art high voltage GaN HEMT and low voltage silicon MOSFET technologies—offering superior reliability and performance.

Transphorm GaN offers improved efficiency over silicon, through lower gate charge, lower crossover loss, and smaller reverse recovery charge.

#### Related Literature

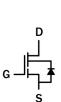
- ANOOOO: Recommended External Circuitry for GaN FETs
- ANOOO3: Printed Circuit Board Layout and Probing
- ANOO10: Paralleling GaN FETs

#### **Ordering Information**

Part Number	Package	Package Configuration
TP65H035WS	3 lead TO-247	Source

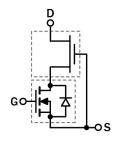
#### TP65H035WS TO-247 (top view)







**Cascode Schematic Symbol** 



**Cascode Device Structure** 

#### **Features**

- JEDEC qualified GaN technology
- Dynamic R<sub>DS(on)eff</sub> production tested
- · Robust design, defined by
  - Intrinsic lifetime tests
  - Wide gate safety margin
  - Transient over-voltage capability
- Very low Q<sub>RR</sub>
- Reduced crossover loss
- · RoHS compliant and Halogen-free packaging

#### **Benefits**

- Improves efficiency/operation frequencies over Si
- Enables AC-DC bridgeless totem-pole PFC designs
  - Increased power density
  - Reduced system size and weight
  - Overall lower system cost
- Easy to drive with commonly-used gate drivers
- · GSD pin layout improves high speed design

#### **Applications**

- Datacom
- Broad industrial
- PV inverter
- · Servo motor

Key Specifications		
V <sub>DSS</sub> (V)	650	
V <sub>(TR)DSS</sub> (V)	800	
$R_{DS(on)eff}(m\Omega)\;max^*$	41	
Q <sub>RR</sub> (nC) typ	178	
Q <sub>G</sub> (nC) typ	24	

<sup>\*</sup> Dynamic on-resistance; see Figures 17 and 18

<b>Common Topology Power Recommendations</b>			
CCM bridgeless totem-pole* 3770W max			
Hard-switched inverter**	4600W max		

Conditions: F<sub>SW</sub>=45kHz; T<sub>J</sub>=115°C; T<sub>HEATSINK</sub>=90°C; insulator between device and heatsink (6 mil Sil-Pad® K-10); power de-rates at lower voltages with constant current

- VIN=230VAC; VOUT=390VDC
- $V_{IN}$ =380 $V_{DC}$ ;  $V_{OUT}$ =240 $V_{AC}$

### **Absolute Maximum Ratings** (T<sub>c</sub>=25 °C unless otherwise stated.)

Symbol	Parameter		Limit Value	Unit
V <sub>DSS</sub>	Drain to source voltage (T <sub>J</sub> = -5	Drain to source voltage (T <sub>J</sub> = -55 °C to 150 °C)		
V <sub>(TR)DSS</sub>	Transient drain to source voltage	ge <sup>a</sup>	800	V
V <sub>GSS</sub>	Gate to source voltage	Gate to source voltage		
P <sub>D</sub>	Maximum power dissipation @	Γ <sub>C</sub> =25°C	156	W
	Continuous drain current @Tc=	25°C <sup>b</sup>	46.5	A
l <sub>D</sub>	Continuous drain current @T <sub>C</sub> =	Continuous drain current @T <sub>C</sub> =100°C b		A
I <sub>DM</sub>	Pulsed drain current (pulse wid	Pulsed drain current (pulse width: 10µs)		A
(di/dt) <sub>RDMC</sub>	Reverse diode di/dt, repetitive °		1800	A/µs
(di/dt) <sub>RDMT</sub>	Reverse diode di/dt, transient d		3800	A/µs
Tc	Operating temperature	Case	-55 to +150	°C
TJ	Operating temperature	Junction	-55 to +150	°C
Ts	Storage temperature		-55 to +150	°C
T <sub>SOLD</sub>	Soldering peak temperature <sup>e</sup>		260	°C
-	Mounting Torque		80	N cm

#### Notes:

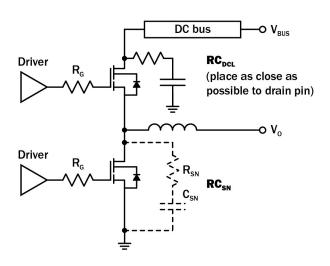
- a. In off-state, spike duty cycle D<0.01, spike duration <1 $\mu$ s
- For increased stability at high current operation, see Circuit Implementation on page 3 b.
- Continuous switching operation
- d. ≤300 pulses per second for a total duration ≤20 minutes
- For 10 sec., 1.6mm from the case

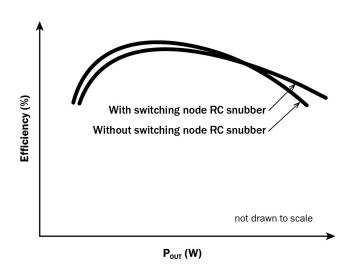
#### **Thermal Resistance**

Symbol	Parameter	Maximum	Unit
R <sub>ØJC</sub>	Junction-to-case	0.8	°C/W
R <sub>OJA</sub>	Junction-to-ambient	40	°C/W

2

### **Circuit Implementation**





**Simplified Half-bridge Schematic** 

**Efficiency vs Output Power** 

Recommended gate drive: (0V, 12V) with R<sub>G</sub> =  $30\Omega$ 

Required DC Link RC Snubber (RC <sub>DCL</sub> ) <sup>a</sup>		Recommended Switching Node RC Snubber (RC <sub>SN</sub> ) b, c		
	$[10nF + 8\Omega] \times 2$	200pF + 5Ω		

#### Notes:

- a. RC<sub>DCL</sub> should be placed as close as possible to the drain pin
- b. A switching node RC snubber (C, R) is recommended for high switching currents (>70% of IRDMC1 or IRDMC2; see page 5 for IRDMC1 and IRDMC2)
- c.  $I_{RDM}$  values can be increased by increasing  $R_{G}$  and  $C_{SN}$

### **Electrical Parameters** (T<sub>J</sub>=25 °C unless otherwise stated)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions	
Forward Device Characteristics							
$V_{(BL)DSS}$	Drain-source voltage	650	_	_	V	V <sub>GS</sub> =0V	
$V_{GS(th)}$	Gate threshold voltage	3.3	4	4.8	V		
$\Delta V_{\text{GS(th)}}\!/T_{\text{J}}$	Gate threshold voltage temperature coefficient	_	-6.5	_	mV/°C	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =1mA	
R <sub>DS(on)eff</sub>	Drain-source on-resistance a	_	35	41	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> =30A	
NDS(on)eπ	Drain-source off-resistance	_	72	_	11122	V <sub>GS</sub> =10V, I <sub>D</sub> =30A, T <sub>J</sub> =150°C	
I <sub>DSS</sub>	Drain-to-source leakage current	_	2.5	25	μA	V <sub>DS</sub> =650V, V <sub>GS</sub> =0V	
IDSS	Dialit-to-source leakage current	_	15	_	μΛ	V <sub>DS</sub> =650V, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C	
	Gate-to-source forward leakage current	_	_	400	ю А	V <sub>GS</sub> =20V	
I <sub>GSS</sub>	Gate-to-source reverse leakage current	_	_	-400	- nA	V <sub>GS</sub> =-20V	
C <sub>ISS</sub>	Input capacitance	_	1500	_		V <sub>GS</sub> =0V, V <sub>DS</sub> =400V, <i>f</i> =1MHz	
Coss	Output capacitance	_	190	_	pF		
C <sub>RSS</sub>	Reverse transfer capacitance	_	10	_			
$C_{\text{O(er)}}$	Output capacitance, energy related b	_	290	_	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V to 400V	
C <sub>O(tr)</sub>	Output capacitance, time related c	_	440	_	ρι		
Q <sub>G</sub>	Total gate charge	_	24	36		$V_{DS}$ =400V, $V_{GS}$ =0V to 10V, $I_{D}$ =32A	
$Q_{GS}$	Gate-source charge	_	10	_	nC		
Q <sub>GD</sub>	Gate-drain charge	_	6	_			
Qoss	Output charge	_	178	_	nC	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V to 400V	
t <sub>D(on)</sub>	Turn-on delay	_	69	_		V <sub>DS</sub> =400V, V <sub>GS</sub> =0V to 12V,	
t <sub>R</sub>	Rise time	_	13.5	_	ns		
t <sub>D(off)</sub>	Turn-off delay	_	98.5	_	] 113	$I_D=32A$ , $R_G=30\Omega$	
t <sub>F</sub>	Fall time	_	11.5	_			

#### Notes:

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a. Dynamic on-resistance; see Figures 17 and 18 for test circuit and conditions

b. Equivalent capacitance to give same stored energy as V<sub>DS</sub> rises from 0V to 400V

c. Equivalent capacitance to give same charging time as  $V_{\text{DS}}$  rises from  $\mbox{OV}$  to  $400\mbox{V}$ 

### **Electrical Parameters** (T<sub>J</sub>=25 °C unless otherwise stated)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions
Reverse Dev	Reverse Device Characteristics					
Is	Reverse current	_	_	29.5	А	V <sub>GS</sub> =0V, T <sub>C</sub> =100°C ≤20% duty cycle
$V_{SD}$	D	_	1.8	_	V	V <sub>GS</sub> =0V, I <sub>S</sub> =32A
VSD	Reverse voltage <sup>a</sup>	_	1.3	_		V <sub>GS</sub> =0V, I <sub>S</sub> =15A
t <sub>RR</sub>	Reverse recovery time	_	65	_	ns	I <sub>S</sub> =30A, V <sub>DD</sub> =400V,
$Q_{RR}$	Reverse recovery charge	_	178	_	nC	di/dt=1000A/μs
(di/dt) <sub>RDMC</sub>	Reverse diode di/dt, repetitive b	_	_	1800	A/µs	
I <sub>RDMC1</sub>	Reverse diode switching current, repetitive (dc) c, e	_	_	28	А	Circuit implementation and parameters on page 3
I <sub>RDMC2</sub>	Reverse diode switching current, repetitive (ac) c, e	_	_	35	А	Circuit implementation and parameters on page 3
(di/dt) <sub>RDMT</sub>	Reverse diode di/dt, transient d	_	_	3800	A/µs	
I <sub>RDMT</sub>	Reverse diode switching current, transient d,e			Circuit implementation and parameters on page 3		

#### Notes:

- a. Includes dynamic  $R_{DS(on)}$  effect
- b. Continuous switching operation
- c. Definitions: dc = dc-to-dc converter topologies; ac = inverter and PFC topologies, 50-60Hz line frequency
- d. ≤300 pulses per second for a total duration ≤20 minutes

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### **Typical Characteristics** (T<sub>C</sub>=25 °C unless otherwise stated)

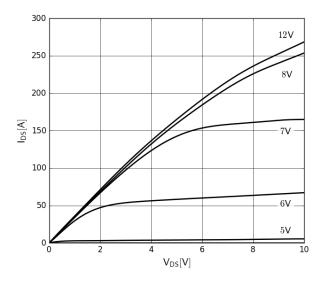


Figure 1. Typical Output Characteristics T<sub>J</sub>=25 °C

Parameter: V<sub>GS</sub>

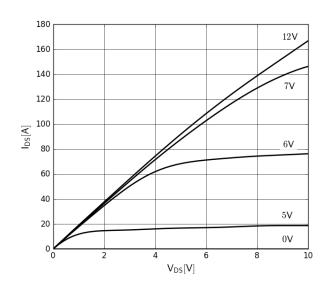


Figure 2. Typical Output Characteristics T<sub>J</sub>=150 °C

Parameter: V<sub>GS</sub>

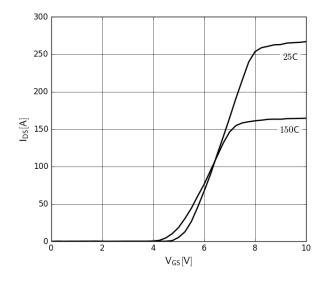


Figure 3. Typical Transfer Characteristics

 $V_{DS}$ =10V, parameter:  $T_J$ 

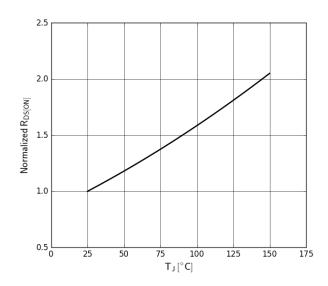


Figure 4. Normalized On-resistance

I<sub>D</sub>=30A, V<sub>GS</sub>=10V

### **Typical Characteristics** (T<sub>C</sub>=25 °C unless otherwise stated)

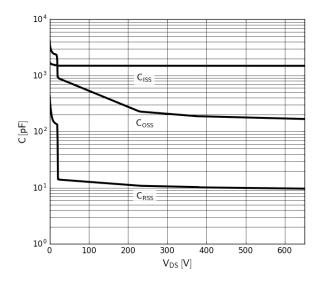


Figure 5. Typical Capacitance  $V_{GS}$ =0V, f=1MHz

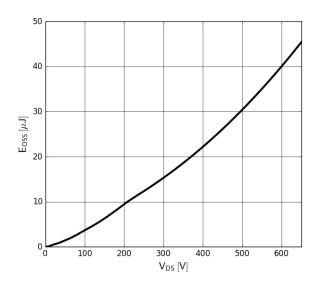


Figure 6. Typical Coss Stored Energy

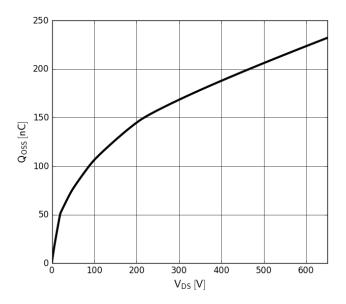


Figure 7. Typical Qoss

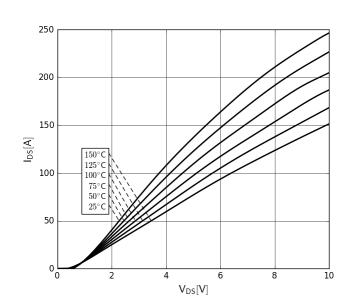


Figure 8. Forward Characteristics of Rev. Diode  $I_S {=} f(V_{SD}), \ parameter {:} \ T_J$ 

### **Typical Characteristics** (T<sub>C</sub>=25 °C unless otherwise stated)

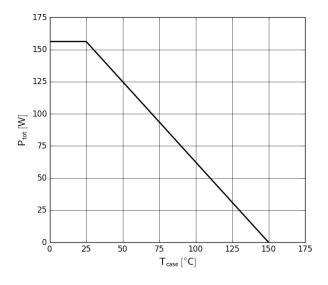


Figure 9. Power Dissipation

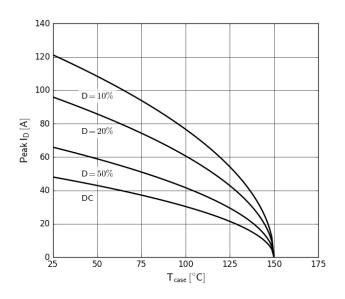


Figure 10. Current Derating Pulse width  $\leq$  10µs,  $V_{GS} \geq$  10V

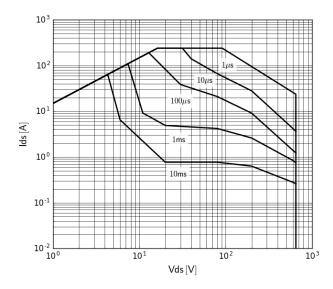


Figure 11. Safe Operating Area  $T_C=25$  °C

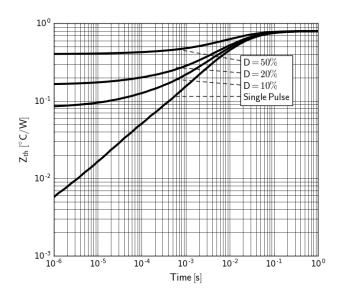
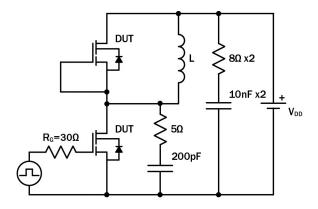


Figure 12. Transient Thermal Resistance

#### **Test Circuits and Waveforms**



**Figure 13. Switching Time Test Circuit** (see circuit implementation on page 3 for methods to ensure clean switching)

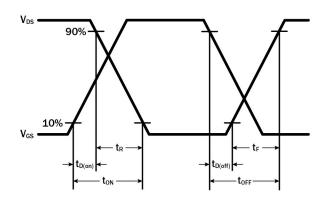


Figure 14. Switching Time Waveform

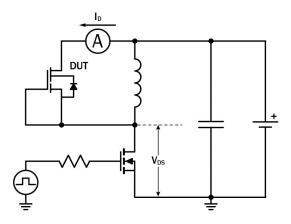


Figure 15. Diode Characteristics Test Circuit

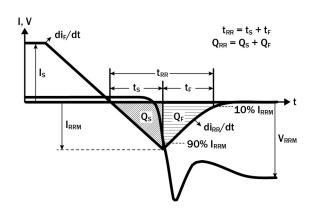


Figure 16. Diode Recovery Waveform

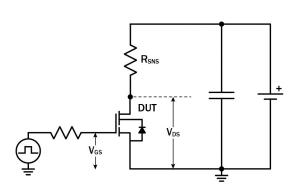


Figure 17. Dynamic R<sub>DS(on)eff</sub> Test Circuit

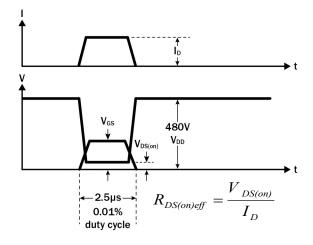


Figure 18. Dynamic R<sub>DS(on)eff</sub> Waveform

#### **Design Considerations**

The fast switching of GaN devices reduces current-voltage crossover losses and enables high frequency operation while simultaneously achieving high efficiency. However, taking full advantage of the fast switching characteristics of GaN switches requires adherence to specific PCB layout guidelines and probing techniques.

Before evaluating Transphorm GaN devices, see application note <u>Printed Circuit Board Layout and Probing for GaN Power Switches</u>. The table below provides some practical rules that should be followed during the evaluation.

#### When Evaluating Transphorm GaN Devices:

DO	DO NOT
Minimize circuit inductance by keeping traces short, both in the drive and power loop	Twist the pins of TO-220 or TO-247 to accommodate GDS board layout
Minimize lead length of TO-220 and TO-247 package when mounting to the PCB	Use long traces in drive circuit, long lead length of the devices
Use shortest sense loop for probing; attach the probe and its ground connection directly to the test points	Use differential mode probe or probe ground clip with long wire
See AN0003: Printed Circuit Board Layout and Probing	

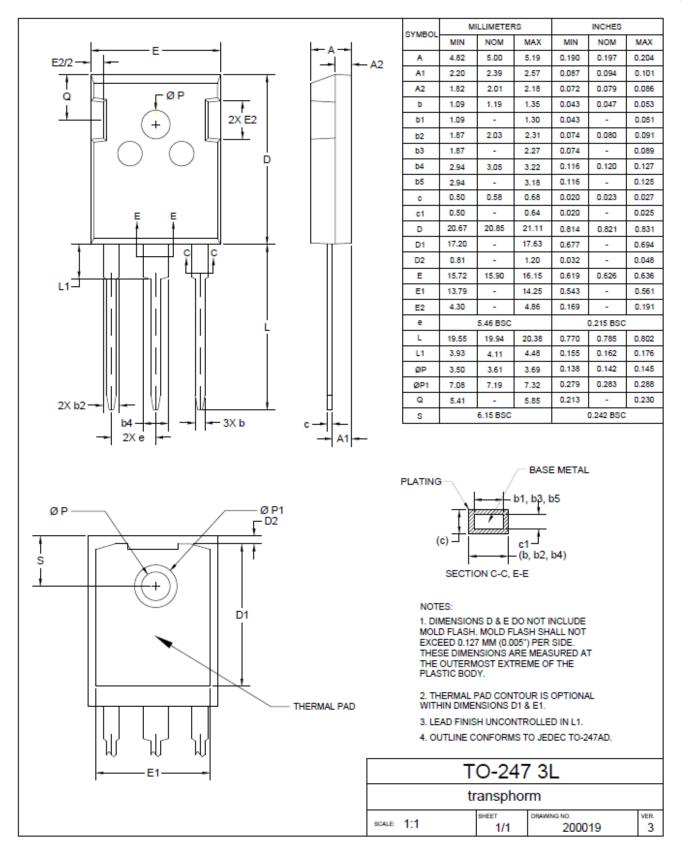
#### **GaN Design Resources**

The complete technical library of GaN design tools can be found at <a href="mailto:transphormusa.com/design">transphormusa.com/design</a>:

- Evaluation kits
- Application notes
- · Design guides
- · Simulation models
- Technical papers and presentations

#### Mechanical

#### 3 Lead TO-247 Package



# **Revision History**

Version	Date	Change(s)	
0	11/22/2017	Initial	
1	6/13/2018	Datasheet completed	
2	11/20/2018	Add max mouting torque	
3	2/1/2019	Correct Power dissipation label on Figure 9 and SOA at 10ms	